

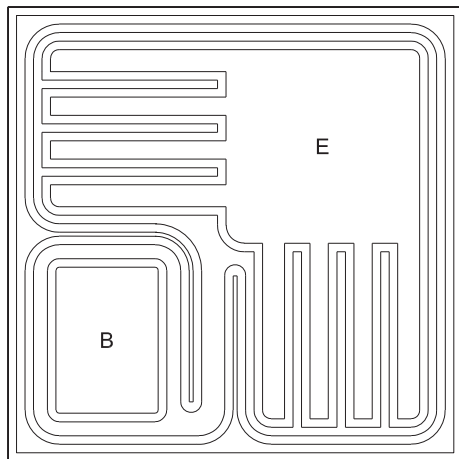
PROCESS CP230
Power Transistor
NPN - Silicon Darlington Transistor Chip



PROCESS DETAILS

Process	EPITAXIAL BASE
Die Size	80 x 80 MILS
Die Thickness	8.0 MILS
Base Bonding Pad Area	18 x 27 MILS
Emitter Bonding Pad Area	34 x 34 MILS
Top Side Metalization	Al - 30,000Å
Back Side Metalization	Ti/Pd/Ag - 20,000Å

GEOMETRY



BACKSIDE COLLECTOR R1

GROSS DIE PER 4 INCH WAFER

1,445

PRINCIPAL DEVICE TYPES

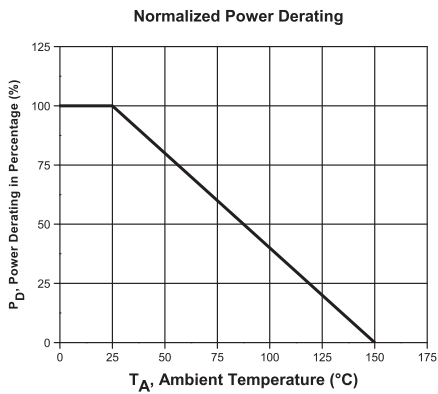
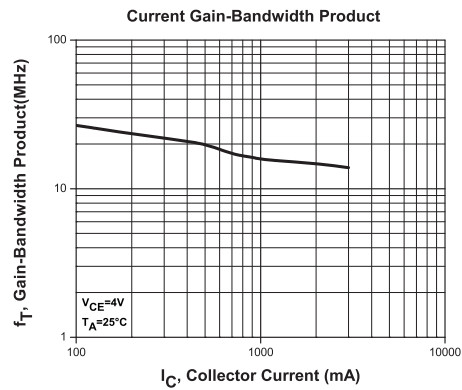
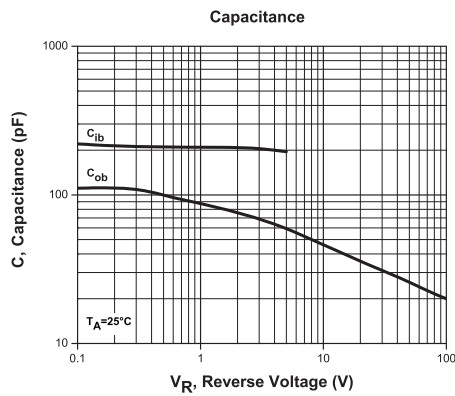
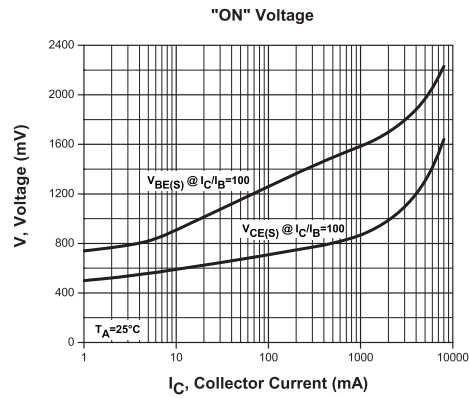
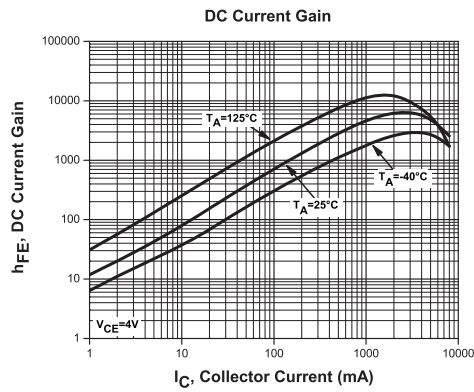
CZT122

CJD122

R2 (22-March 2010)

PROCESS CP230

Typical Electrical Characteristics



R2 (22-March 2010)